



Automatic RF Techniques Group

56th Measurement Conference

Metrology and Test for RF Telecommunications

Boulder, Colorado • November 30-December 1, 2000

FIRST CALL FOR PAPERS

Conference Officers

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The Automatic RF Techniques Group will hold its 56th ARFTG Measurement Conference in Boulder, Colorado near the site of the National Institute of Standards Boulder Laboratories to celebrate NIST's centennial. The two-day conference will cover all aspects of microwave metrology with a focus on the burgeoning field of RF telecommunications.

Join us as we explore a host of cutting edge microwave measurements for RF telecommunications. We encourage you to submit original papers demonstrating your approach to metrology and testing of RF telecommunication systems on topics including but not limited to:

- adjacent and cochannel interference
- measurement of bit error rate, including eye diagrams and constellation diagrams
- signal-to-noise ratio of microwave and broadband signals
- device, system, and channel characterization
- experimentally-based behavioral modeling
- time-domain measurement, characterization, and models of communication systems
- large-signal measurements related to telecommunications

We also invite submissions to our three **Special Sessions:**

Temporal Measurements for Microwave Systems
Accuracy in Microwave RF Measurement
NIST: 100 Years of Metrology

Deadlines

September 11th Electronic Abstract/Summary in PDF format due
October 16th Electronic full camera ready paper in PDF format due

Paper acceptance and classification will be communicated by September 21st 2000.

Instructions to Authors

Contributed papers will be presented as 20-minute talks or in the interactive poster session, and published in the 56th ARFTG Digest. You can express preference for the interactive poster session together with your submission. These papers are treated equally and are introduced during the session.

We request that authors submit electronically a one page abstract and a 500 to 1000 word summary, including illustrations, to allow for evaluation with regard to the interests of the participants and the quality and novelty of the work. Please make your submission electronically in PDF format to Kate Remley at remley@boulder.nist.gov. Additional information can be found in the *Abstract/Summary Submission Instructions* on our organizations' Web site, <http://www.arftg.org>.

Exhibits

The 56th ARFTG Conference also offers an outstanding exhibition opportunity. Please contact our Exhibits Chair directly for further information.



www.arftg.org

